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Comparison of Dislocation Characterization by Electron Channeling Contrast Imaging and Cross-Correlation Electron Backscattered Diffraction

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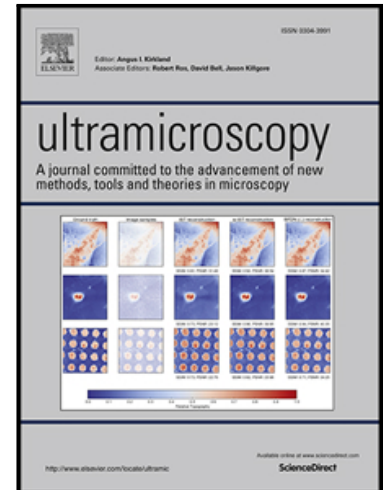
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Highlights

- Locations of ECCI imaged dislocations generally match CC-EBSD GND distributions.
- ECCI derived dislocation densities replicate CC-EBSD GND densities.
- Good agreement with dislocation characterization by the two techniques.
- ECCI is optimal for low dislocation density.
- CC-EBSD is better for high dislocation density.

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